

Notice of References Cited

Application/Control No.

10/825,116

Applicant(s)/Patent Under
Reexamination
SETO, YOJI

Examiner

IAN JEN

Art Unit

3664

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,269,298 B1	07-2001	Seto, Yoji	701/96
*	B	US-2001/0016798 A1	08-2001	Kodaka et al.	701/301
*	C	US-2002/0099491 A1	07-2002	Akabori et al.	701/96
*	D	US-2002/0091479 A1	07-2002	Maruko et al.	701/96
*	E	US-2002/0111733 A1	08-2002	Akabori et al.	701/96
*	F	US-2002/0134602 A1	09-2002	Kobayashi et al.	180/169
*	G	US-6,470,257 B1	10-2002	Seto, Yoji	701/96
*	H	US-2002/0169538 A1	11-2002	Yamamura et al.	701/96
*	I	US-2003/0028311 A1	02-2003	Seto et al.	701/96
*	J	US-2003/0067219 A1	04-2003	Seto et al.	303/193
*	K	US-2003/0201878 A1	10-2003	Bai et al.	340/435
*	L	US-6,640,181 B2	10-2003	Akabori et al.	701/96
*	M	US-6,650,990 B2	11-2003	Yamamura et al.	701/96

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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NON-PATENT DOCUMENTS

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	U	
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	X	

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	Examiner IAN JEN		Art Unit 3664	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,687,595 B2	02-2004	Seto et al.	701/96
*	B	US-2004/0145238 A1	07-2004	Seto et al.	303/193
*	C	US-6,769,504 B2	08-2004	Kobayashi et al.	180/169
*	D	US-2004/0193351 A1	09-2004	Takahashi et al.	701/070
*	E	US-2004/0193374 A1	09-2004	Hac et al.	701/301
*	F	US-2004/0236491 A1	11-2004	Seto, Yoji	701/096
*	G	US-6,856,887 B2	02-2005	Akabori et al.	701/96
*	H	US-2005/0125153 A1	06-2005	Matsumoto et al.	701/300
*	I	US-7,015,805 B2	03-2006	Knoop et al.	340/467
*	J	US-7,016,783 B2	03-2006	Hac et al.	701/301
*	K	US-7,099,764 B2	08-2006	Seto et al.	701/70
*	L	US-2007/0032914 A1	02-2007	Kondoh et al.	701/001
*	M	US-2007/0129891 A1	06-2007	Yano et al.	701/301

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0208485 A1	09-2007	Yamamura et al.	701/93
*	B	US-2008/0033621 A1	02-2008	Nakamura et al.	701/65
*	C	US-2008/0078600 A1	04-2008	Inoue et al.	180/170
*	D	US-2008/0270001 A1	10-2008	Seto et al.	701/93
*	E	US-2008/0312834 A1	12-2008	Noda et al.	701/301
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	W				
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